

AM27S23, AM27S23A

2,048-Bit (256x8) Bipolar RAM

The AM27S23 (256-words by 8-bits) is a Schottky TTL Programmable Read-Only Memory (PROM).

This device has three-state outputs, compatible with low-power Schottky bus standards capable of satisfying the requirements of a variety of microprogrammable controls, mapping functions, code conversion, or logic replacement. Easy word depth expansion is facilitated by active LOW $(\overline{G}_1, \overline{G}_2)$ output enables.

Rochester Electronics Manufactured Components

Rochester branded components are manufactured using either die/wafers purchased from the original suppliers or Rochester wafers recreated from the original IP. All recreations are done with the approval of the OCM.

Parts are tested using original factory test programs or Rochester developed test solutions to guarantee product meets or exceeds the OCM data sheet.

Quality Overview

- ISO-9001
- AS9120 certification
- Qualified Manufacturers List (QML) MIL-PRF-38535
 - Class Q Military
 - Class V Space Level
- Qualified Suppliers List of Distributors (QSLD)
 - Rochester is a critical supplier to DLA and meets all industry and DLA standards.

Rochester Electronics, LLC is committed to supplying products that satisfy customer expectations for quality and are equal to those originally supplied by industry manufacturers.

The original manufacturer's datasheet accompanying this document reflects the performance and specifications of the Rochester manufactured version of this device. Rochester Electronics guarantees the performance of its semiconductor products to the original OEM specifications. 'Typical' values are for reference purposes only. Certain minimum or maximum ratings may be based on product characterization, design, simulation, or sample testing.



Am27S23/Am27S23A

2,048-Bit (256x8) Bipolar PROM

DISTINCTIVE CHARACTERISTICS

- High Speed
- Highly reliable, ultra-fast programming Platinum-Silicide fuses
- High programming yield

- Low-current PNP inputs
- High-current open-collector and three-state outputs
- Fast chip select

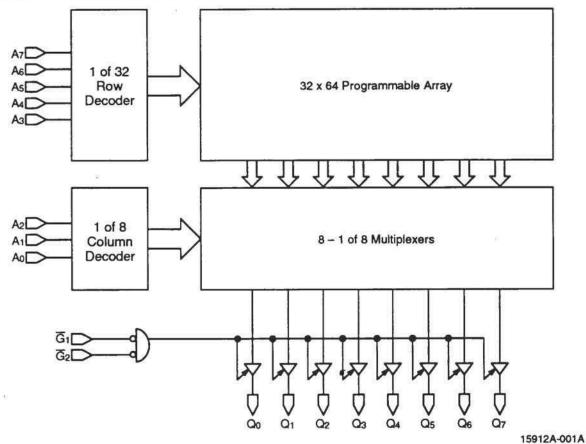
GENERAL DESCRIPTION

The Am27S23 (256-words by 8-bits) is a Schottky TTL Programmable Read-Only Memory (PROM).

This device has three-state outputs, compatible with low-power Schottky bus standards capable of satisfying

the requirements of a variety of microprogrammable controls, mapping functions, code conversion, or logic replacement. Easy word depth expansion is facilitated by active LOW $(\overline{G}_1, \overline{G}_2)$ output enables.

FUNCTIONAL BLOCK DIAGRAM



PRODUCT SELECTOR GUIDE

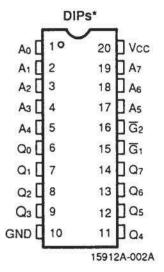
Three-State Part Number	Am2	7S23A	Am27S23			
Address Access Time	30 ns	40 ns	45 ns	50 ns		
Operating Range	С	М	С	М		

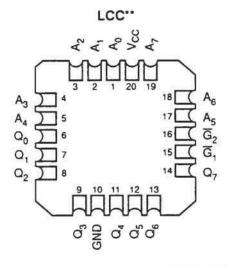
Publication# 15912 Rev. A Amendment/9 Issue Date: August 1991

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CONNECTION DIAGRAMS

Top View

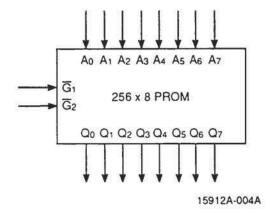




15912A-003A

Note: Pin 1 is marked for orientation.

LOGIC SYMBOL



^{*}Also available in a 20-pin Flatpack. Pinout identical to DIPs.

^{**}Also available in a 20-pin PLCC. Pinout identical to LCC

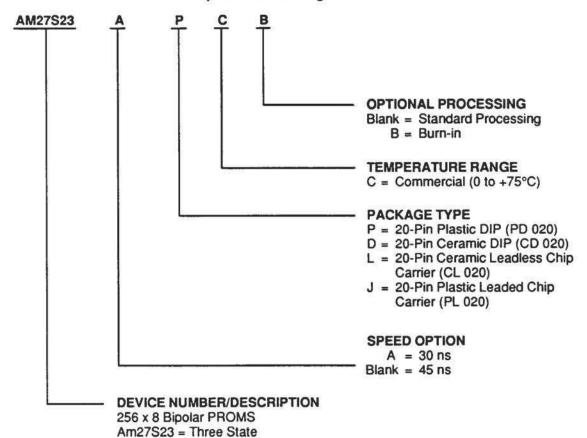


ORDERING INFORMATION Standard Products

AMD products are available in several packages and operating ranges. The ordering number (Valid Combination) is formed by a combination of:

Device Number

Device Number
Speed Option (if applicable)
Package Type
Temperature Range
Optional Processing



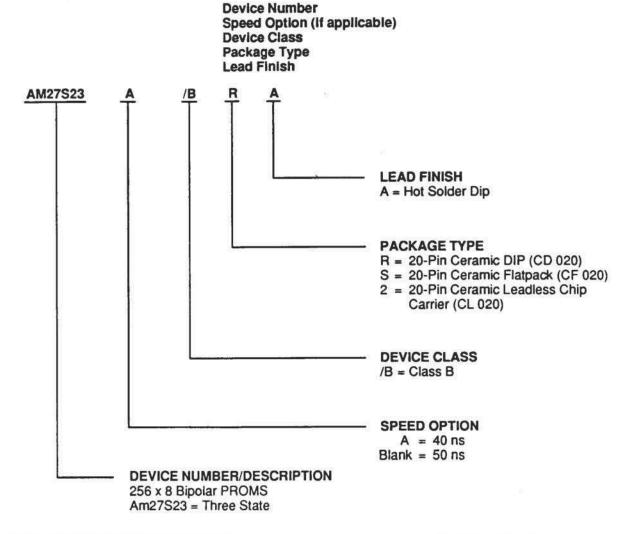
Valid Combinations						
AM27S23	PC, PCB, DC, DCB,					
AM27S23A	LC, LCB, JC, JCB					

Valid Combinations

The Valid Combinations table lists configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

ORDERING INFORMATION APL Products

AMD programmable logic products for Aerospace and Defense applications are available with several ordering options. APL (Approved Products List) products are fully compliant with MIL-STD-883 requirements. The order number (Valid Combination) is formed by a combination of:



Valid C	ombinations
AM27S23	/BRA, /BSA, /B2A
AM27S23A	76NA, 763A, 762A

Valid Combinations

The Valid Combinations table lists configurations planned to be supported in volume for this device. Consult the local AMD sales office to confirm availability of specific valid combinations, to check on newly released combinations, and to obtain additional data on AMD's standard military grade products.

Note: Marked with AMD logo.

Group A Tests

Group A Tests consist of Subgroups: 1, 2, 3, 7, 8, 9, 10, 11.

Military Burn-In

Military burn-in is in accordance with the current revision of MIL-STD-883, Test Methods 1015, Conditions A through E. Test conditions are selected at AMD's option.



PIN DESCRIPTION

A0- A7

Address (Inputs)

The 9-bit field presented at the address inputs selects one of 256 memory locations to be read from.

Q0- Q7

Data Output Port

The outputs whose state represents the data read from the selected memory locations.

 $\overline{G}_1, \overline{G}_2$

Output Enables (Input)

Provides direct control of the Q-output buffers. Outputs disabled forces all three-state outputs to a floating or high-impedance state.

Enable = \overline{G}

Disable = G

Vcc

Device Power Supply Pin

The most positive of the logic power supply pins.

GND

Device Power Supply Pin

The most negative of the logic power supply pins.



ABSOLUTE MAXIMUM RATINGS

Storage Temperature

-65°C to +150°C

Ambient Temperature

with Power Applied Supply Voltage with

-55°C to +125°C

Respect to Ground

-0.5 V to +7.0 V

DC Voltage Applied to Outputs

(Except During Programming)

-0.5 V to Vcc Max.

DC Voltage Applied to Outputs During Programming

Output Current into Outputs During

Programming (Max. Duration of 1 sec) 250 mA

DC Input Voltage

-0.5 V to +5.5 V

DC Input Current

-30 mA to +5 mA

Stresses above those listed under Absolute Maximum Ratings may cause permanent device failure. Functionality at or above these limits is not implied. Exposure to Absolute Maximum Ratings for extended periods may affect device reliability. Programming conditions may differ.

OPERATING RANGES

Commercial (C) Devices

Ambient Temperature (T_A)

0 to +75°C

Supply Voltage (Vcc)

+4.75 V to +5.25 V

Military (M) Devices*

Case Temperature (Tc)

-55 to +125°C

Supply Voltage (Vcc)

+4.5 V to +5.5 V

Operating ranges define those limits between which the functionality of the device is guaranteed.

*Military product 100% tested at Tc = +25°C, +125°C, and -55°C

DC CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A. Subgroups 1, 2, 3 are tested unless otherwise noted)

21 V

Parameter Symbol	77 India - Target T. Anno 19 19 September 1990 Anno 1990		Min.	Тур.	Max.	Unit
V _{OH} (Note 1)	Output HIGH Voltage	V _{CC} = Min., I _{OH} = -2.0 mA V _{IN} = V _{IH} or V _{IL}	2.4	*		٧
Vol	Output LOW Voltage	V _{CC} = Min., I _{OH} = 16 mA V _{IN} = V _{IH} or V _{IL}			0.50	٧
VIH	Input HIGH Level	Guaranteed input Logical HIGH voltage for all outputs (Note 2)	2.0			٧
VIL	Input LOW Level	Guaranteed input logical LOW voltage for all inputs (Note 2)			0.8	٧
l _{IL}	Input LOW Current	Vcc = Max., V _{IN} = 0.45 V	Q1		-0.250	mA
lıн	Input HIGH Current	Vcc = Max., Vin = 2.7 V			25	μА
Isc (Note 1)	Output Short-Circuit Current	Vcc = Max., Vout = 0.0 V (Note 3)	-20		-90	mA
lcc	Power Supply Current	All inputs = GND, Vcc = Max.			160	mA
Vı	Input Clamp Voltage	Vcc = Min., I _{IN} = -18 mA			-1.2	٧
ICEX	Output Leakage Current	$V_{CC} = Max$ $V_{G_1} = 2.4 \text{ V}$ (Note 1) $V_0 = V_{CC}$ $V_{OUT} = 0.4 \text{ V}$			40 -40	μА
Cin	Input Capacitance	V _{IN} = 2.0 V @ f = 1 MHz (Note 4) V _{CC} = 5 V; T _A = 25°C		4		pF
Соит	Output Capacitance	Vout = 2.0 V @ f = 1 MHz (Note 4) Vcc = 5 V; TA = 25°C		8]

Notes:

- This applies to three-state devices only.
- 2. VIL and VIH are input conditions of output tests and are not themselves directly tested. VIL and VIH are absolute voltages with respect to device ground and include all overshoots due to system and/or tester noise. Do not attempt to test these values without suitable equipment.
- 3. Not more than one output should be shorted at a time. Duration of the short circuit should not be more than one second.
- These parameters are not 100% tested, but are periodically evaluated at initial characterization and at any time the design is modified where capacitance may be affected.



SWITCHING CHARACTERISTICS over operating ranges unless otherwise specified (for APL Products, Group A, Subgroups 9, 10, 11 are tested unless otherwise noted*)

No.	Parameter Symbol	Parameter Description	"A" Version			Standard Version					
			COM'L		MIL		COM'L		MIL		
			MIn.	Max.	Min.	Max.	Min.	Max.	MIn.	Max.	Units
1	TAVQV	Address Valid to Output Valid Access Time		30		40		45		50	ns
2	TGVQZ	Delay from Output Enable Valid to Output Hi-Z		25		30		25		30	ns
3	TGVQV	Delay from Output Enable Valid to Output Valid	75.7	25		30		25		30	ns

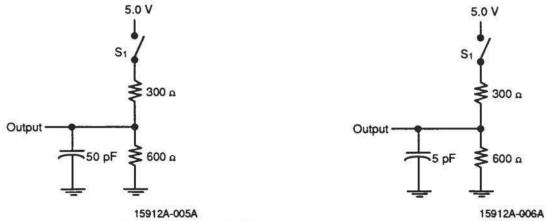
See also Switching Test Circuits.

Notes:

- 1. Tests are performed with input transition time of 5 ns or less, timing reference levels of 1.5 V, and input pulse levels of 0 to 3.0 V using test load in Figure A.
- TGVQZ is measured at steady state HIGH output voltage -0.5 V and steady state LOW output voltage +0.5 V output levels using the test load in Figure B.

^{*}Subgroups 7 and 8 apply to functional tests.

SWITCHING TEST CIRCUITS



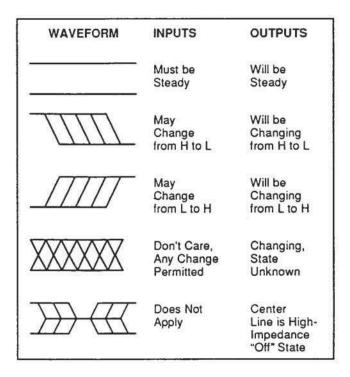
A. Output Load for all A - C Tests Except TGVQZ

B. Output Load for TGVQZ

Notes:

- 1. All device test loads should be located within 2" of device output pin.
- 2. S1 is open for Output Data High to Hi-Z and Hi-Z to Output Data High tests. S1 is closed for all other AC tests.
- 3. Load capacitance includes all stray and fixture capacitance.

KEY TO SWITCHING WAVEFORMS



KS000010

